

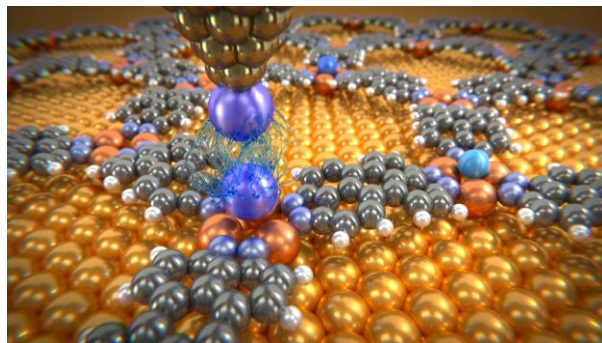
# Force measurement by atomic force microscopy with a molecular tip at low temperature

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Recent progress in atomic force microscopy allows us to see inner structures of molecules adsorbed on surfaces [1]. In such measurements, a reactive metal tip is usually terminated by a small molecule or an inert rare gas atom. Such high-resolution imaging is beneficial to study single and self-assembled molecules as well as chemical reactions. Besides high-resolution imaging, force measurements became more reliable and even quantitative since the structure of the tip apex, at least the front-most-atom, can be controlled in experiment.

In this presentation, force spectroscopic measurements with different molecular tips (i.e. Xe-tip for van der Waals force detection [2] and CO-tip for the intermolecular bond detection [3]) will be discussed (Fig. 1). Besides the small atom and molecule, the tip can be also terminated with a large molecule or a polymer. By moving the tip vertically, we measured desorption phenomena of repeat polyfluorene units [4]. We found that the incommensurability between the unit length and the lattice distance plays a role in the friction. Since the fluorene units are connected to each other by a single bond, the incommensurability is not high. Using a stiffer material in-plane, a lower friction can be expected. In fact, the super lubricity was detected when graphene nanoribbon was slid on Au(111) [5].



**Figure 1** Schematic drawing of the pair-wise van der Waals force measurement.

[1] L. Gross, F. Mohn, N. Moll, P. Liljeroth, and G. Meyer, *Science*, **325**, 1110 (2008).

[2] S. Kawai, A. S. Foster, T. Björkman, S. Nowakowsaka, J. Björk, F. Federici Canova, L. H. Gade, T. A. Jung, and E. Meyer, *Nature Communications*, **7**, 11559 (2016).

[3] S. Kawai, T. Nishiuchi, T. Kodama, P. Spijker, R. Pawlak, T. Meier, J. Tracey, T. Kubo, E. Meyer and A. S. Foster, *Science Advances* **3**, e1603258 (2017).

[4] S. Kawai, M. Koch, E. Gnecco, A. Sadeghi, R. Pawlak, Th. Glatzel, J. Schwarz, S. Goedecker, S. Hecht, A. Baratoff, L. Grill, and E. Meyer, *Proc. Natl. Acad. Sci. USA* **111**, 3968 (2014).

[5] S. Kawai, A. Benassi, E. Gnecco, H. Söde, R. Pawlak, K. Mullen, D. Passerone, C. Pignedoli, P. Ruffieux, R. Fasel, and E. Meyer, *Science*, **351**, 957 (2016).

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